

Notice of References Cited	Application/Control No. 10/725,434	Applicant(s)/Patent Under Reexamination IINUMA, TOSHIHIKO	
	Examiner Patricia A. George	Art Unit 1765	Page 1 of 1

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	C	US-6,599,370	07-2003	Skee, David C.	134/3
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.